



Image AF/2829

GR 00 P 1679

BOX AF

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By: 

Date: February 25, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : 09/826,594 Confirmation No. 4825  
Applicant : Dieter Kantz et al.  
Filed : April 5, 2001  
TC/A.U. : 2829  
Examiner : Ernest F. Karlsen  
Title : Test Configuration for the Functional Testing  
of a Semiconductor Chip  
  
Docket No. : GR 00 P 1679  
Customer No. : 24131

BOX AF

Hon. Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT under 37 C.F.R. § 1.116**

S i r :

In response to the final Office action dated December 2, 2003,  
please amend the above-identified application as follows:

**Amendments to the Claims** are reflected in the listing of  
claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 5 of this paper.